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, "Front Matter: Volume 10178," Proc. SPIE 10178, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII, 1017801 (21 June 2017); doi: 10.1117/12.2280573

Event: SPIE Defense + Security, 2017, Anaheim, CA, United States

PROCEEDINGS OF SPIE

Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII

**Gerald C. Holst
Keith A. Krapels**
Editors

**11–12 April 2017
Anaheim, California, United States**

Sponsored and Published by
SPIE

Volume 10178

Proceedings of SPIE 0277-786X, V. 10178

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII, edited by Gerald C. Holst,
Keith A. Krapels, Proc. of SPIE Vol. 10178, 1017801 · © 2017 SPIE
CCC code: 0277-786X/17/\$18 · doi: 10.1117/12.2280573

Proc. of SPIE Vol. 10178 1017801-1

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Author(s), "Title of Paper," in *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII*, edited by Gerald C. Holst, Keith A. Krapels, Proceedings of SPIE Vol. 10178 (SPIE, Bellingham, WA, 2017) Seven-digit Article CID Number.

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510608573

ISBN: 9781510608580 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) • Fax +1 360 647 1445

SPIE.org

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Introduction

This is the 28th year for our conference, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing*. Over the years, we have witnessed the creation of IR focal plane arrays, IR scene projectors, MTF measurement techniques, and the Night Vision Integrated Performance Model (NVIPM). As government and private industry interests change, our conference has had swings in the number of papers presented and attendees. Currently, we seem to be on a rise.

We have not written an introduction to these proceedings for many years. The papers are self-explanatory and do not require any comment. We are pleased that all the authors provided professional presentations and quality manuscripts.

In 2016, our conference committee created a Best Paper Award based upon the presentation. In case of ties, the most downloaded paper is considered. We are proud to recognize:

Best presentation

David P. Haefner, Brian P. Teaney, and Bradley L. Preece, "Modeling demosaicing of color corrected cameras in the NV-IPM", Proc. SPIE 9820, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVII*, 982009 (May 3, 2016); doi:10.1117/12.2235781.

Most downloaded paper (first 3 months after publication)

Daniel Wegner and Endre Repasi, "Image based performance analysis of thermal imagers ", Proc. SPIE 9820, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVII*, 982016 (May 3, 2016); doi:10.1117/12.2223629.

For 2017:

Best presentation

Austin A. Richards and Martin Huebner, "A new radiometric unit of measure to characterize SWIR illumination ", Proc. SPIE 10178, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII*, 101780C (May 3, 2017); doi:10.1117/12.2261459.

Most downloaded paper (first 3 months after publication)

McKenna R. Lovejoy and Mark A. Wickert, "Testing of next-generation nonlinear calibration based non-uniformity correction techniques using SWIR devices ", Proc. SPIE 10178, *Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXVIII*, 1017803 (May 3, 2017); doi:10.1117/12.2262127.

Thank you to all who presented, the attendees, and our excellent conference committee.

**Gerald C. Holst
Keith A. Krapels**